

Notice of References Cited	Application/Control No. 10/805,343	Applicant(s)/Patent Under Reexamination IKENO ET AL.	
	Examiner Chriss S. Yoder, III	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0135827 A1	09-2002	Saika, Toshihiro	358/513
*	B	US-6,697,108 B1	02-2004	Chen et al.	348/241
*	C	US-6,473,538 B2	10-2002	Kozuka, Hiraku	382/312
*	D	US-2002/0186312 A1	12-2002	Stark, Moshe	348/302
*	E	US-5,262,871 A	11-1993	Wilder et al.	348/307
*	F	US-6,888,568 B1	05-2005	Neter, Sarit	348/222.1
*	G	US-2001/0030700	10-2001	Mabuchi et al.	348/302
*	H	US-6,580,455 B1	06-2003	Wang et al.	348/308
*	I	US-6,794,627 B2	09-2004	Lyon et al.	250/208.1
*	J	US-2002/0145669 A1	10-2002	Umeda et al.	348/220.1
*	K	US-2004/0169752 A1	09-2004	Stark, Moshe	348/302
*	L	US-5,818,526 A	10-1998	Nomoto, Tetsuo	348/302
*	M	US-5,717,199	02-1998	Carbone et al.	250/208.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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